

# Search Notes



Application/Control No.

10/760,060

Examiner

Nhan T. Le

Applicant(s)/Patent under Reexamination

JIN ET AL.

Art Unit

2618

## SEARCHED

Class	Subclass	Date	Examiner
455	103 127.1 127.2	08/25/06	N. Le
	232.1 234.1		
	245.1 250.1		
	522.1 561		
370	318, 336 347		
	347		
375	295, 296		
	345		
Updated search			
		02/21/07	N. Le
		09/10/07	N. Le

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
prior art search Sec			
interference search			
		09/10/07	N. Le

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Enst search	08/25/06	N. Le
	02/21/07	
	09/10/07	
Interference search	09/10/07	